## **Supporting information**

## Terbium doped LiLuF<sub>4</sub> nanocrystal scintillator-based flexible composite film for high resolution X-ray imaging

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Fig. S1. The EDS spectrum of LiLuF<sub>4</sub>:15%Tb nanocrystals (NCs).



Fig. S2. The photoluminescence excitation (PLE) spectra of LiLuF<sub>4</sub>:15%Tb NCs.



Fig. S3. The FT-IR spectrum of LiLuF<sub>4</sub>:15%Tb NCs and oleic acid molecules.



**Fig. S4.** (a) RL spectrum of LiLuF<sub>4</sub>: 3%Sm, LiLuF<sub>4</sub>: 15%Tb and LiLuF<sub>4</sub>:15%Tb, 3%Sm NCs. (b) The photograph of LiLuF<sub>4</sub>: 3% Sm, LiLuF<sub>4</sub>:15%Tb and LiLuF4: 15%Tb, 3%Sm NCs under X-ray irradiation.



**Fig. S5.** The radioluminescence spectrum of epoxy resin polymer film (black, EP FILM) and instrument noise (red).



**Fig. S6.** (a) The EDS characterization of LiLuF<sub>4</sub>:15%Tb NCs-EP composite film. (b) The EDS spectrum of PET layer. (c) The EDS spectrum of LiLuF<sub>4</sub>:15%Tb NCs-EP composite layer.



Fig. S7. The schematic diagram of self-built X-ray imaging device.



Fig. S8. (a) The photograph of 135 μm CsI:Tl commercial scintillation sheet; (b) The X-ray image of 135 μm CsI:Tl commercial scintillation sheet.



**Fig. S9.** Biological imaging of LiLuF<sub>4</sub>:15%Tb NCs composite thin films.